

# S-5715 Series

# HIGH-SPEED / MIDDLE-SPEED LOW CURRENT CONSUMPTION BOTH POLES / UNIPOLAR DETECTION TYPE HALL IC

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Rev.2.3\_02

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The S-5715 Series, developed by CMOS technology, is a high-accuracy Hall IC that operates with high-speed / middle-speed detection and low current consumption.

The output voltage changes when the S-5715 Series detects the intensity level of flux density. Using the S-5715 Series with a magnet makes it possible to detect the open / close and rotation state in various devices.

High-density mounting is possible by using the small SOT-23-3 or the super-small SNT-4A packages.

Due to its high-accuracy magnetic characteristics, the S-5715 Series can make operation's dispersion in the system combined with magnet smaller.

Caution This product is intended to use in general electronic devices such as consumer electronics, office equipment, and communications devices. Before using the product in medical equipment or automobile equipment including car audio, keyless entry and engine control unit, contact to ABLIC Inc. is indispensable.

# Features

- Pole detection<sup>\*1</sup>:
- Detection logic for magnetism<sup>\*1</sup>:
- Output form<sup>\*1</sup>:
- Magnetic sensitivity:
- Operating cycle (current consumption)<sup>\*1</sup>:

Detection of both poles, S pole or N pole Active "L", active "H" Nch open-drain output, CMOS output  $B_{OP} = 3.0 \text{ mT}$  typ. Product with both poles detection  $t_{CYCLE} = 0.10 \text{ ms} (1400 \ \mu\text{A}) \text{ typ.}$  $t_{CYCLE} = 0.90 \text{ ms} (155 \ \mu\text{A}) \text{ typ.}$  $t_{CYCLE} = 5.70 \text{ ms} (26 \ \mu\text{A}) \text{ typ.}$ Product with S pole or N pole detection  $t_{CYCLE} = 0.05 \text{ ms} (1400 \ \mu\text{A}) \text{ typ.}$  $t_{CYCLE} = 1.25 \text{ ms} (60 \ \mu\text{A}) \text{ typ.}$  $t_{CYCLE} = 6.05 \text{ ms} (13 \ \mu\text{A}) \text{ typ.}$  $V_{DD} = 2.7 \text{ V to } 5.5 \text{ V}$ Ta =  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ 

• Power supply voltage range:

- Lead-free (Sn 100%), halogen-free<sup>\*2</sup>

\*1. The option can be selected.

\*2. Refer to "
Product Name Structure" for details.

# Applications

- Plaything, portable game
- Home appliance
- Housing equipment
- Industrial equipment

### Packages

- SOT-23-3
- SNT-4A

# Block Diagrams

1. Nch open-drain output product





2. CMOS output product



\*1. Parasitic diode

Figure 2

#### Product Name Structure

1. Product name



#### 2. Packages

Package Name	Dimension	Таре	Reel	Land
SOT-23-3	MP003-C-P-SD	MP003-C-C-SD	MP003-Z-R-SD	-
SNT-4A	PF004-A-P-SD	PF004-A-C-SD	PF004-A-R-SD	PF004-A-L-SD

#### 3. Product name list

#### 3.1 SOT-23-3

#### 3. 1. 1 Nch open-drain output product

#### Table 2

Product Name	Operating Cycle (t <sub>CYCLE</sub> )	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B <sub>OP</sub> )
S-5715CNDL1-M3T1U	5.70 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715CNSL1-M3T1U	6.05 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715DNDL1-M3T1U	0.90 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715DNSL1-M3T1U	1.25 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715ENDL1-M3T1U	0.10 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715ENSL1-M3T1U	0.05 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715ENSH1-M3T1U	0.05 ms	Nch open-drain output	S pole	Active "H"	3.0 mT typ.

Remark Please contact our sales office for products other than the above.

#### 3. 1. 2 CMOS output product

#### Table 3

Product Name	Operating Cycle (t <sub>CYCLE</sub> )	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B <sub>OP</sub> )
S-5715CCDL1-M3T1U	5.70 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715CCSL1-M3T1U	6.05 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715DCDL1-M3T1U	0.90 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715DCSL1-M3T1U	1.25 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715ECDL1-M3T1U	0.10 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715ECSL1-M3T1U	0.05 ms	CMOS output	S pole	Active "L"	3.0 mT typ.

Remark Please contact our sales office for products other than the above.

#### 3.2 SNT-4A

# 3. 2. 1 Nch open-drain output product

#### Table 4

Product Name	Operating Cycle (t <sub>CYCLE</sub> )	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B <sub>OP</sub> )
S-5715CNDL1-I4T1U	5.70 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715CNSL1-I4T1U	6.05 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715CNNL1-I4T1U	6.05 ms	Nch open-drain output	N pole	Active "L"	3.0 mT typ.
S-5715DNDL1-I4T1U	0.90 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715DNSL1-I4T1U	1.25 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715ENDL1-I4T1U	0.10 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.

**Remark** Please contact our sales office for products other than the above.

#### 3. 2. 2 CMOS output product

#### Table 5

Product Name	Operating Cycle (t <sub>CYCLE</sub> )	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B <sub>OP</sub> )
S-5715CCDL1-I4T1U	5.70 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715CCSL1-I4T1U	6.05 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715CCNL1-I4T1U	6.05 ms	CMOS output	N pole	Active "L"	3.0 mT typ.
S-5715DCDL1-I4T1U	0.90 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715DCSL1-I4T1U	1.25 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715ECDL1-I4T1U	0.10 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.

**Remark** Please contact our sales office for products other than the above.

# Pin Configurations

# 1. SOT-23-3



Pin No.	Symbol	Description
1	VSS	GND pin
2	VDD	Power supply pin
3	OUT	Output pin

Table 6

Figure 3

### 2. SNT-4A

Т	ор	view
1 2	P	4 3

Figure 4

Pin No.	Symbol	Description
1	VDD	Power supply pin
2	VSS	GND pin
3	NC <sup>*1</sup>	No connection
4	OUT	Output pin

Table 7

**\*1.** The NC pin is electrically open.

The NC pin can be connected to the VDD pin or the VSS pin.

# Absolute Maximum Ratings

Table 8

			(Ta = +25°C unless otherwis	se specified)
	Item	Symbol	Absolute Maximum Rating	Unit
Power supply voltage		V <sub>DD</sub>	$V_{SS}{-}0.3$ to $V_{SS}{+}7.0$	V
Output current		I <sub>OUT</sub>	±2.0	mA
Nch open-drain output           Output voltage         product		V <sub>OUT</sub>	$V_{SS}{-}0.3$ to $V_{SS}{+}7.0$	V
	CMOS output product		$V_{\text{SS}} - 0.3$ to $V_{\text{DD}} + 0.3$	V
Power dissipation	SOT-23-3	D	430*1	mW
Power dissipation	SNT-4A	- P <sub>D</sub>	300 <sup>*1</sup>	mW
Operation ambient temperature		T <sub>opr</sub>	-40 to +85	°C
Storage temperature		T <sub>stg</sub>	-40 to +125	°C

**\*1.** When mounted on board

[Mounted board]

(1) Board size:(2) Name:

114.3 mm × 76.2 mm × t1.6 mm JEDEC STANDARD51-7

Caution The absolute maximum ratings are rated values exceeding which the product could suffer physical damage. These values must therefore not be exceeded under any conditions.



Figure 5 Power Dissipation of Package (When Mounted on Board)

# Electrical Characteristics

## 1. Product with both poles detection

#### 1.1 S-5715CxDxx

#### Table 9

			(Ta = +25°C, V <sub>DD</sub> = 5.0	V, V <sub>SS</sub> =	0 V unl	ess othe	erwise s	pecified)
Item	Symbol	Con	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	$V_{DD}$	_		2.7	5.0	5.5	V	_
Current consumption	I <sub>DD</sub>	Average value		_	26.0	40.0	μA	1
Output voltage V <sub>ot</sub>		Nch open-drain output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	-	-	0.4	V	2
	V <sub>OUT</sub>	CMOS output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	_	_	0.4	V	2
			Output transistor Pch, $I_{OUT} = -2 \text{ mA}$	V <sub>DD</sub> - 0.4	_	_	V	3
Leakage current	$I_{LEAK}$	Nch open-drain output production output transistor Nch, $V_{\rm C}$		_	_	1	μA	4
Awake mode time	t <sub>AW</sub>		_	_	0.10	-	ms	_
Sleep mode time	t <sub>SL</sub>				5.60	-	ms	-
Operating cycle	t <sub>CYCLE</sub>	$t_{AW} + t_{SL}$		-	5.70	12.00	ms	-

#### 1.2 S-5715DxDxx

#### Table 10

			(Ta = +25°C, V <sub>DD</sub> = 5.0	V, V <sub>SS</sub> =	0 V unl	ess othe	erwise s	pecified)
Item	Symbol	Con	dition	Min.	Тур.	Max.	Unit	Test Circuit
Power supply voltage	$V_{DD}$		-	2.7	5.0	5.5	V	_
Current consumption	I <sub>DD</sub>	verage value		_	155.0	230.0	μA	1
Output voltage V <sub>OUT</sub>		Nch open-drain output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	_	_	0.4	V	2
	V <sub>OUT</sub>	CMOS output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	_	_	0.4	V	2
			Output transistor Pch, $I_{OUT} = -2 \text{ mA}$	V <sub>DD</sub> - 0.4	-	_	V	3
Leakage current	$I_{LEAK}$		ch open-drain output product putput transistor Nch, $V_{OUT}$ = 5.5 V		_	1	μA	4
Awake mode time	t <sub>AW</sub>		_	_	0.10	_	ms	-
Sleep mode time	t <sub>SL</sub>		_		0.80	_	ms	_
Operating cycle	t <sub>CYCLE</sub>	$t_{AW} + t_{SL}$		_	0.90	2.00	ms	_

#### . . **.** . .

# HIGH-SPEED / MIDDLE-SPEED LOW CURRENT CONSUMPTION BOTH POLES / UNIPOLAR DETECTION TYPE HALL IC S-5715 Series Rev.2.3\_02

#### 1.3 S-5715ExDxx

#### Table 11

Item	Symbol	Cond	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	V <sub>DD</sub>	-	_		5.0	5.5	V	_
Current consumption	I <sub>DD</sub>	Average value		-	1400.0	2000.0	μA	1
Output voltage V <sub>OUT</sub>		Nch open-drain output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	-	_	0.4	V	2
	V <sub>OUT</sub>	CMOS output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	-	_	0.4	V	2
		CMOS output product Output transistor Pch, $I_{OUT} = -2 \text{ mA}$		V <sub>DD</sub> - 0.4	_	-	V	3
Leakage current	$I_{LEAK}$		Nch open-drain output product Output transistor Nch, V <sub>OUT</sub> = 5.5 V		_	1	μA	4
Awake mode time	t <sub>AW</sub>	_		-	0.10	_	ms	-
Sleep mode time	t <sub>SL</sub>	_		Ι	0.00	_	ms	_
Operating cycle	t <sub>CYCLE</sub>	$t_{AW} + t_{SL}$	i <sub>AW</sub> + t <sub>SL</sub>		0.10	0.20	ms	_

#### (Ta = $+25^{\circ}$ C, V<sub>DD</sub> = 5.0 V, V<sub>SS</sub> = 0 V unless otherwise specified)

#### 2. Product with S pole or N pole detection

#### 2.1 S-5715CxSxx, S-5715CxNxx

#### Table 12

			(Ta = +25°C, V <sub>DD</sub> = 5.0	V, V <sub>SS</sub> =	0 V unl	ess othe	erwise s	pecified)
Item	Symbol	Con	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	$V_{DD}$		-	2.7	5.0	5.5	V	-
Current consumption	I <sub>DD</sub>	Average value		_	13.0	20.0	μA	1
Output voltage V <sub>OUT</sub>	Nch open-drain output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	_	_	0.4	V	2	
	V <sub>OUT</sub>	CMOS output product	Output transistor Nch, $I_{OUT} = 2 \text{ mA}$	_	Ι	0.4	V	2
			Output transistor Pch, $I_{OUT} = -2 \text{ mA}$	V <sub>DD</sub> - 0.4	-	-	V	3
Leakage current	$I_{LEAK}$		Nch open-drain output product Output transistor Nch, $V_{OUT}$ = 5.5 V		Ι	1	μA	4
Awake mode time	t <sub>AW</sub>		_		0.05	_	ms	_
Sleep mode time	t <sub>SL</sub>	_		_	6.00	-	ms	_
Operating cycle	t <sub>CYCLE</sub>	t <sub>AW</sub> + t <sub>SL</sub>		-	6.05	12.00	ms	_

#### 2. 2 S-5715DxSxx, S-5715DxNxx

#### Table 13

(Ta = +25°C, V <sub>DD</sub> = 5.0 V, V <sub>SS</sub> = 0 V unless otherwise specifie					peemeu)			
Item	Symbol	Con	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	$V_{DD}$		_	2.7	5.0	5.5	V	_
Current consumption	I <sub>DD</sub>	Average value		_	60.0	90.0	μA	1
Output voltage V <sub>OUT</sub>		Nch open-drain output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	_	I	0.4	V	2
	V <sub>OUT</sub>	CMOS output product $\begin{array}{l} \text{Output transistor Nch,} \\ I_{OUT} = 2 \text{ mA} \\ \text{Output transistor Pch,} \\ I_{OUT} = -2 \text{ mA} \end{array}$	_	Ι	0.4	V	2	
			-	V <sub>DD</sub> - 0.4	Ι	_	V	3
Leakage current	$I_{LEAK}$		Nch open-drain output product Output transistor Nch, V <sub>OUT</sub> = 5.5 V		Ι	1	μA	4
Awake mode time	t <sub>AW</sub>	_		_	0.05	_	ms	-
Sleep mode time	t <sub>SL</sub>	_		-	1.20	-	ms	-
Operating cycle	t <sub>CYCLE</sub>	$t_{AW} + t_{SL}$	t <sub>AW</sub> + t <sub>SL</sub>		1.25	2.50	ms	_

# (Ta = +25°C, $V_{DD}$ = 5.0 V, $V_{SS}$ = 0 V unless otherwise specified)

#### 2.3 S-5715ExSxx, S-5715ExNxx

#### Table 14

Item	Symbol	Con	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	$V_{DD}$		_		5.0	5.5	V	_
Current consumption	I <sub>DD</sub>	Average value		-	1400.0	2000.0	μA	1
Output voltage V <sub>OUT</sub>		Nch open-drain output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	-	_	0.4	V	2
	V <sub>OUT</sub>	CMOS output product	Output transistor Nch, I <sub>OUT</sub> = 2 mA	-	_	0.4	V	2
		CMOS output product Output transistor Pch, $I_{OUT} = -2 \text{ mA}$		V <sub>DD</sub> – 0.4	_	-	V	3
Leakage current	$I_{\text{LEAK}}$		Nch open-drain output product Output transistor Nch, V <sub>OUT</sub> = 5.5 V		_	1	μA	4
Awake mode time	t <sub>AW</sub>		_		0.05	_	ms	_
Sleep mode time	t <sub>SL</sub>			_	0.00	_	ms	_
Operating cycle	t <sub>CYCLE</sub>	$t_{AW} + t_{SL}$	i <sub>AW</sub> + t <sub>SL</sub>		0.05	0.10	ms	_

#### $(Ta = +25^{\circ}C, V_{DD} = 5.0 \text{ V}, V_{SS} = 0 \text{ V}$ unless otherwise specified)

#### Magnetic Characteristics

#### 1. Product with both poles detection

#### Table 15

			(Ta = +2	5°C, V <sub>DD</sub> =	5.0 V, V <sub>SS</sub>	= 0 V unle	ss other	wise specified)
Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Operation paint*1	S pole	B <sub>OPS</sub>	-	1.4	3.0	4.0	mT	5
Operation point <sup>*1</sup>	N pole	B <sub>OPN</sub>	_	-4.0	-3.0	-1.4	mT	5
Release point <sup>*2</sup>	S pole	B <sub>RPS</sub>	-	1.1	2.2	3.7	mT	5
Release point	N pole	B <sub>RPN</sub>	_	-3.7	-2.2	-1.1	mT	5
Hysteresis width <sup>*3</sup>	S pole	B <sub>HYSS</sub>	$B_{HYSS} = B_{OPS} - B_{RPS}$	_	0.8	I	mT	5
	N pole	B <sub>HYSN</sub>	$B_{HYSN} =  B_{OPN} - B_{RPN} $	-	0.8	-	mT	5

#### 2. Product with S pole detection

#### Table 16

			(Ta = +2	5°C, V <sub>DD</sub> =	5.0 V, V <sub>SS</sub>	= 0 V unle	ess other	wise specified)
Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Operation point <sup>*1</sup>	S pole	B <sub>OPS</sub>	-	1.4	3.0	4.0	mT	5
Release point <sup>*2</sup>	S pole	B <sub>RPS</sub>	-	1.1	2.2	3.7	mT	5
Hysteresis width*3	S pole	B <sub>HYSS</sub>	B <sub>HYSS</sub> = B <sub>OPS</sub> – B <sub>RPS</sub>	-	0.8	-	mT	5

#### 3. Product with N pole detection

#### Table 17

(Ta =  $+25^{\circ}$ C, V<sub>DD</sub> = 5.0 V, V<sub>SS</sub> = 0 V unless otherwise specified)

Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Operation point <sup>*1</sup>	N pole	B <sub>OPN</sub>	-	-4.0	-3.0	-1.4	mT	5
Release point <sup>*2</sup>	N pole	B <sub>RPN</sub>	_	-3.7	-2.2	-1.1	mT	5
Hysteresis width*3	N pole	B <sub>HYSN</sub>	$B_{HYSN} =  B_{OPN} - B_{RPN} $	I	0.8	I	mT	5

\*1. B<sub>OPN</sub>, B<sub>OPS</sub>: Operation points

 $B_{OPN}$  and  $B_{OPS}$  are the values of magnetic flux density when the output voltage (V<sub>OUT</sub>) is inverted after the magnetic flux density applied to the S-5715 Series by the magnet (N pole or S pole) is increased (the magnet is moved closer). Even when the magnetic flux density exceeds  $B_{OPN}$  or  $B_{OPS}$ ,  $V_{OUT}$  retains the status.

\*2. B<sub>RPN</sub>, B<sub>RPS</sub>: Release points

 $B_{RPN}$  and  $B_{RPS}$  are the values of magnetic flux density when the output voltage (V<sub>OUT</sub>) is inverted after the magnetic flux density applied to the S-5715 Series by the magnet (N pole or S pole) is decreased (the magnet is moved further away). Even when the magnetic flux density falls below  $B_{RPN}$  or  $B_{RPS}$ , V<sub>OUT</sub> retains the status.

#### \*3. B<sub>HYSN</sub>, B<sub>HYSS</sub>: Hysteresis widths

 $B_{HYSN}$  and  $B_{HYSS}$  are the difference between  $B_{OPN}$  and  $B_{RPN}$ , and  $B_{OPS}$  and  $B_{RPS}$ , respectively.

**Remark** The unit of magnetic density mT can be converted by using the formula 1 mT = 10 Gauss.

# Test Circuits



\*1. Resistor (R) is unnecessary for the CMOS output product.

Figure 6 Test Circuit 1



Figure 7 Test Circuit 2



Figure 8 Test Circuit 3



Figure 9 Test Circuit 4



\*1. Resistor (R) is unnecessary for the CMOS output product.

Figure 10 Test Circuit 5

# Standard Circuit



\*1. Resistor (R) is unnecessary for the CMOS output product.

#### Figure 11

Caution The above connection diagram and constant will not guarantee successful operation. Perform thorough evaluation using the actual application to set the constant.

# Operation

#### 1. Direction of applied magnetic flux

The S-5715 Series detects the flux density which is vertical to the marking surface.

In product with both poles detection, the output voltage (V<sub>OUT</sub>) is inverted when the S pole or N pole is moved closer to the marking surface.

In product with S pole detection, the output voltage ( $V_{OUT}$ ) is inverted when the S pole is moved closer to the marking surface.

In product with N pole detection, the output voltage ( $V_{OUT}$ ) is inverted when the N pole is moved closer to the marking surface.

Figure 12 and Figure 13 show the direction in which magnetic flux is being applied.



#### 2. Position of Hall sensor

Figure 14 and Figure 15 show the position of Hall sensor.

The center of this Hall sensor is located in the area indicated by a circle, which is in the center of a package as described below.

2.2 SNT-4A

The following also shows the distance (typ. value) between the marking surface and the chip surface of a package.

#### 2.1 SOT-23-3



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#### 3. Basic operation

The S-5715 Series changes the output voltage level ( $V_{OUT}$ ) according to the level of the magnetic flux density (N pole or S pole) applied by a magnet.

The following explains the operation when the magnetism detection logic is active "L".

#### 3.1 Product with both poles detection

When the magnetic flux density vertical to the marking surface exceeds  $B_{OPN}$  or  $B_{OPS}$  after the S pole or N pole of a magnet is moved closer to the marking surface of the S-5715 Series,  $V_{OUT}$  changes from "H" to "L". When the S pole or N pole of a magnet is moved further away from the marking surface of the S-5715 Series and the magnetic flux density is lower than  $B_{RPN}$  or  $B_{RPS}$ ,  $V_{OUT}$  changes from "L" to "H".

Figure 16 shows the relationship between the magnetic flux density and  $V_{\mbox{\scriptsize OUT}}.$ 





#### 3.2 Product with S pole detection

When the magnetic flux density vertical to the marking surface exceeds  $B_{OPS}$  after the S pole of a magnet is moved closer to the marking surface of the S-5715 Series,  $V_{OUT}$  changes from "H" to "L". When the S pole of a magnet is moved further away from the marking surface of the S-5715 Series and the magnetic flux density is lower than  $B_{RPS}$ ,  $V_{OUT}$  changes from "L" to "H".

Figure 17 shows the relationship between the magnetic flux density and  $V_{OUT}$ .



Figure 17

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#### 3.3 Product with N pole detection

When the magnetic flux density vertical to the marking surface exceeds  $B_{OPN}$  after the N pole of a magnet is moved closer to the marking surface of the S-5715 Series,  $V_{OUT}$  changes from "H" to "L". When the N pole of a magnet is moved further away from the marking surface of the S-5715 Series and the magnetic flux density is lower than  $B_{RPN}$ ,  $V_{OUT}$  changes from "L" to "H".

Figure 18 shows the relationship between the magnetic flux density and  $V_{OUT}$ .



Figure 18

# Precautions

- If the impedance of the power supply is high, the IC may malfunction due to a supply voltage drop caused by feedthrough current. Take care with the pattern wiring to ensure that the impedance of the power supply is low.
- Note that the IC may malfunction if the power supply voltage rapidly changes.
- Do not apply an electrostatic discharge to this IC that exceeds the performance ratings of the built-in electrostatic protection circuit.
- Large stress on this IC may affect on the magnetic characteristics. Avoid large stress which is caused by bend and distortion during mounting the IC on a board or handle after mounting.
- ABLIC Inc. claims no responsibility for any disputes arising out of or in connection with any infringement by products including this IC of patents owned by a third party.

# Marking Specifications

1. SOT-23-3



(4):

(1) to (3): Product code (Refer to Product name vs. Product code.) Lot number

#### Product name vs. Product code

#### 1.1 Nch open-drain output product

Product Name	Pro	oduct Co	de
Product Name	(1)	(2)	(3)
S-5715CNDL1-M3T1U	Х	2	С
S-5715CNSL1-M3T1U	Х	2	L
S-5715DNDL1-M3T1U	Х	2	В
S-5715DNSL1-M3T1U	Х	2	0
S-5715ENDL1-M3T1U	Х	2	R
S-5715ENSL1-M3T1U	Х	2	Α
S-5715ENSH1-M3T1U	Х	2	U

#### 1.2 CMOS output product

Product Name	Product Code				
FIODUCEINAILIE	(1)	(2)	(3)		
S-5715CCDL1-M3T1U	Х	2	М		
S-5715CCSL1-M3T1U	Х	2	Ν		
S-5715DCDL1-M3T1U	Х	2	Р		
S-5715DCSL1-M3T1U	Х	2	Q		
S-5715ECDL1-M3T1U	Х	2	S		
S-5715ECSL1-M3T1U	Х	2	Т		

# HIGH-SPEED / MIDDLE-SPEED LOW CURRENT CONSUMPTION BOTH POLES / UNIPOLAR DETECTION TYPE HALL IC S-5715 Series Rev.2.3\_02

#### 2. SNT-4A

Top view 1 2 (1) (2) (3) 3

(1) to (3): Product code (Refer to Product name vs. Product code.)

#### Product name vs. Product code

#### 2.1 Nch open-drain output product

Product Name	Product Code			
Product Name	(1)	(2)	(3)	
S-5715CNDL1-I4T1U	Х	2	С	
S-5715CNSL1-I4T1U	Х	2	L	
S-5715CNNL1-I4T1U	Х	2	V	
S-5715DNDL1-I4T1U	Х	2	В	
S-5715DNSL1-I4T1U	Х	2	0	
S-5715ENDL1-I4T1U	Х	2	R	

#### 2.2 CMOS output product

Product Name	Product Code			
FIGULE Name	(1)	(2)	(3)	
S-5715CCDL1-I4T1U	Х	2	М	
S-5715CCSL1-I4T1U	Х	2	Ν	
S-5715CCNL1-I4T1U	Х	2	W	
S-5715DCDL1-I4T1U	Х	2	Р	
S-5715DCSL1-I4T1U	Х	2	Q	
S-5715ECDL1-I4T1U	Х	2	S	







No. MP003-C-P-SD-1.1

TITLE	SOT233-C-PKG Dimensions			
No.	MP003-C-P-SD-1.1			
ANGLE	$\oplus$			
UNIT	mm			
ABLIC Inc.				







ABLIC Inc.







※1. ランドパターンの幅に注意してください (0.25 mm min. / 0.30 mm typ.)。 ※2. パッケージ中央にランドパターンを広げないでください (1.10 mm ~ 1.20 mm)。

- 注意 1. パッケージのモールド樹脂下にシルク印刷やハンダ印刷などしないでください。
  - 2. パッケージ下の配線上のソルダーレジストなどの厚みをランドパターン表面から0.03 mm 以下にしてください。
  - 3. マスク開口サイズと開口位置はランドパターンと合わせてください。
  - 4. 詳細は "SNTパッケージ活用の手引き" を参照してください。

%1. Pay attention to the land pattern width (0.25 mm min. / 0.30 mm typ.).

%2. Do not widen the land pattern to the center of the package (1.10 mm to 1.20 mm).

Caution 1. Do not do silkscreen printing and solder printing under the mold resin of the package.

- 2. The thickness of the solder resist on the wire pattern under the package should be 0.03 mm or less from the land pattern surface.
  - 3. Match the mask aperture size and aperture position with the land pattern.
- 4. Refer to "SNT Package User's Guide" for details.
- ※1. 请注意焊盘模式的宽度 (0.25 mm min. / 0.30 mm typ.)。
- ※2. 请勿向封装中间扩展焊盘模式 (1.10 mm ~ 1.20 mm)。
- 注意 1. 请勿在树脂型封装的下面印刷丝网、焊锡。
  - 2. 在封装下、布线上的阻焊膜厚度 (从焊盘模式表面起) 请控制在 0.03 mm 以下。
  - 3. 钢网的开口尺寸和开口位置请与焊盘模式对齐。
  - 4. 详细内容请参阅 "SNT 封装的应用指南"。

TITLE	SNT-4A-A -Land Recommendation
No.	PF004-A-L-SD-4.1
ANGLE	
UNIT	mm
ABLIC Inc.	

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2.4-2019.07